

Up to 6 GHz Low Noise Silicon Bipolar Transistor Chip

Technical Data

AT-41400

Features

- Low Noise Figure: 1.6 dB Typical at 2.0 GHz 3.0 dB Typical at 4.0 GHz
- **High Associated Gain:** 14.5 dB Typical at 2.0 GHz 10.5 dB Typical at 4.0 GHz
- High Gain-Bandwidth Product:
 9.0 GHz Typical f_T

Description

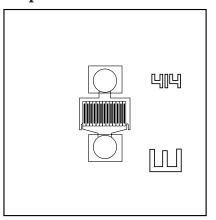
Hewlett-Packard's AT-41400 is a general purpose NPN bipolar transistor chip that offers excellent high frequency performance. The 4 micron emitter-to-emitter pitch enables this transistor to be used in many different functions. The 14 emitter finger interdigitated geometry yields an intermediate sized transistor with impedances

that are easy to match for low noise and moderate power applications. This device is designed for use in low noise, wideband amplifier, mixer and oscillator applications in the VHF, UHF, and microwave frequencies. An optimum noise match near 50 $\,\Omega$ at 1 GHz , makes this device easy to use as a low noise amplifier.

The AT-41400 bipolar transistor is fabricated using Hewlett-Packard's 10 GHz f_T Self-Aligned-Transistor (SAT) process. The die is nitride passivated for surface protection. Excellent device uniformity, performance and reliability are produced by the use of ionimplantation, self-alignment techniques, and gold metalization in the fabrication of this device.

4-99

Chip Outline



5965-8922E

AT-41400 Absolute Maximum Ratings

	TIDDOTAGE MIGHINITATIN 100	011150	
Symbol	Parameter	Units	Absolute Maximum ^[1]
V_{EBO}	Emitter-Base Voltage	V	1.5
V_{CBO}	Collector-Base Voltage	V	20
V_{CEO}	Collector-Emitter Voltage	V	12
I_{C}	Collector Current	mA	60
P_{T}	Power Dissipation [2,3]	mW	500
$T_{\rm j}$	Junction Temperature	°C	200
T_{STG}	Storage Temperature	°C	-65 to 200

TO 4 BT 1 O 1 1 . T 0 4	
Part Number Ordering Information	'n

Part Number	Devices Per Tray
AT-41400-GP4	100

Note: For more information, see "Tape and Reel Packaging for Semiconductor Devices".

Thermal Resistance [2,4]:	
$\theta_{\rm jc} = 95$ °C/W	

Notes:

- 1. Permanent damage may occur if any of these limits are exceeded.
- 2. $T_{MOUNTING SURFACE} = 25$ °C.
- 3. Derate at 10.5 mW/°C for $$T_{MOUNTING\,SURFACE} > 153$ °C.
- 4. The small spot size of this technique results in a higher, though more accurate determination of θ_{jc} than do alternate methods. See MEASUREMENTS section "Thermal Resistance" for more information.

Electrical Specifications, $T_A = 25^{\circ}C$

Symbol	Parameters and Test Conditions ^[1]		Units	Min.	Тур.	Max.
$ S_{21E} ^2$	Insertion Power Gain; $V_{CE} = 8 \text{ V}$, $I_{C} = 25 \text{ mA}$	$f = 2.0 \mathrm{GHz}$ $f = 4.0 \mathrm{GHz}$	dB		12.0 6.5	
P _{1 dB}	Power Output @ 1 dB Gain Compression $V_{CE} = 8 \text{ V}, I_{C} = 25 \text{ mA}$	$f = 2.0 \mathrm{GHz}$ $f = 4.0 \mathrm{GHz}$	dBm		19.0 18.5	
$G_{1 dB}$	1 dB Compressed Gain; $V_{CE} = 8 \text{ V}, I_{C} = 25 \text{ mA}$	$f = 2.0 \mathrm{GHz}$ $f = 4.0 \mathrm{GHz}$	dB		15.0 10.5	
NF _O	Optimum Noise Figure: $V_{CE} = 8 \text{ V}, I_{C} = 10 \text{ mA}$	f = 1.0 GHz f = 2.0 GHz f = 4.0 GHz	dB		1.3 1.6 3.0	
G_{A}	$Gain @ NF_O; V_{CE} = 8 \text{ V}, I_C = 10 \text{ mA}$	$\begin{split} f &= 1.0\mathrm{GHz} \\ f &= 2.0\mathrm{GHz} \\ f &= 4.0\mathrm{GHz} \end{split}$	dB		18.5 14.5 10.5	
f_{T}	Gain Bandwidth Product: $V_{CE} = 8 \text{ V}, I_{C} = 25 \text{ mA}$		GHz		9.0	
h _{FE}	Forward Current Transfer Ratio; $V_{CE} = 8 \text{ V}, I_{C} = 10 \text{ mA}$		_	30	150	300
I_{CBO}	Collector Cutoff Current; $V_{CB} = 8 V$		μA			0.2
I_{EBO}	Emitter Cutoff Current; $V_{EB} = 1 V$		μΑ			1.0
C_{CB}	Collector Base Capacitance ^[2] : $V_{CB} = 8 V$, $f = 1 MHz$		pF		0.17	

Notes:

- 1. RF performance is determined by packaging and testing 10 devices per wafer.
- 2. For this test, the emitter is grounded.

AT-41400 Typical Performance, $T_A = 25$ °C

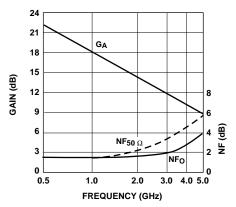


Figure 1. Noise Figure and Associated Gain vs. Frequency. $V_{\rm CE}=8~V,~I_{\rm C}=10mA. \label{eq:VCE}$

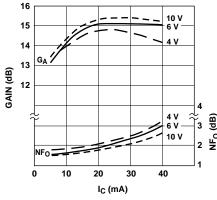


Figure 2. Optimum Noise Figure and Associated Gain vs. Collector Current and Collector Voltage. $f=2.0\ GHz.$

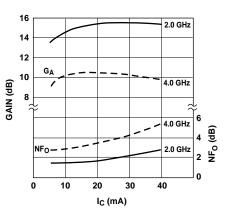


Figure 3. Optimum Noise Figure and Associated Gain vs. Collector Current and Frequency. $V_{CE} = 8 \text{ V}.$

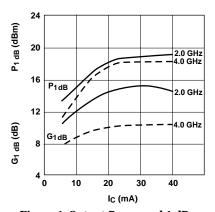


Figure 4. Output Power and 1 dB Compressed Gain vs. Collector Current. $V_{CE} = 8\ V.$

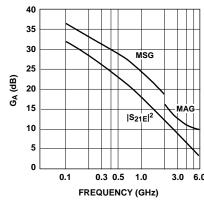


Figure 5. Insertion Power Gain, Maximum Available Gain and Maximum Stable Gain vs. Frequency. $V_{CE}=8\ V,\ I_{C}=25\ mA.$

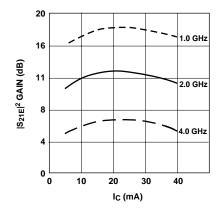


Figure 6. Insertion Power Gain vs. Collector Current and Frequency. $V_{\rm CE}$ = 8 V.

AT-41400 Typical Scattering Parameters, Common Emitter, $Z_O = 50~\Omega$, $T_A = 25^{\circ}C$, $V_{CE} = 8~V$, $I_C = 10~mA$

Freq.	;	$\overline{S_{11}}$		\mathbf{S}_{21}			\mathbf{S}_{12}		S	22
GHz	Mag.	Ang.	dB	Mag.	Ang.	dB	Mag.	Ang.	Mag.	Ang.
0.1	.73	-39	28.3	25.84	159	-39.2	.011	75	.94	-12
0.5	.60	-121	22.2	12.91	113	-30.2	.031	48	.61	-28
1.0	.57	-156	17.2	7.27	94	-28.0	.040	51	.50	-25
1.5	.56	-172	13.7	4.84	84	-26.4	.048	59	.47	-25
2.0	.57	176	11.4	3.71	77	-24.9	.057	66	.46	-24
2.5	.57	170	9.5	2.97	71	-23.6	.066	69	.46	-26
3.0	.60	164	8.0	2.52	64	-22.3	.077	72	.45	-28
3.5	.60	157	6.8	2.18	61	-20.9	.090	77	.47	-29
4.0	.61	152	5.5	1.89	55	-20.1	.099	79	.47	-30
4.5	.63	147	4.7	1.72	51	-18.7	.116	81	.47	-36
5.0	.63	144	3.7	1.53	46	-17.8	.129	80	.48	-40
5.5	.65	139	3.1	1.42	42	-17.0	.141	82	.49	-44
6.0	66	136	2.1	1.28	38	-16.1	.156	83	.50	-47

AT-41400 Typical Scattering Parameters, Common Emitter, $Z_O = 50~\Omega, T_A = 25$ °C, $V_{CE} = 8~V, I_C = 25~mA$

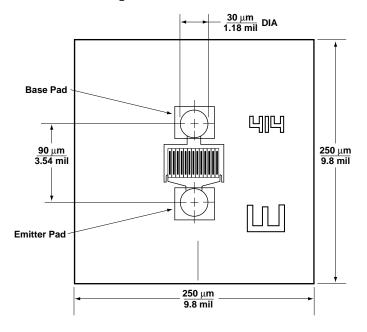
Freq.	1	$\overline{S_{11}}$		\mathbf{S}_{21}			$\mathbf{S_{12}}$		S	22
GHz	Mag.	Ang.	dB	Mag.	Ang.	dB	Mag.	Ang.	Mag.	Ang.
0.1	.56	-60	31.8	39.07	152	-40.9	.009	69	.87	-18
0.5	.54	-145	23.5	15.00	104	-32.8	.023	56	.49	-28
1.0	.54	-170	18.1	8.03	90	-29.6	.033	65	.42	-23
1.5	.55	179	14.5	5.30	82	-26.9	.045	72	.41	-22
2.0	.56	170	12.1	4.04	76	-24.7	.058	75	.41	-23
2.5	.56	165	10.2	3.24	72	-23.1	.070	78	.40	-23
3.0	.58	159	8.8	2.75	65	-21.6	.083	79	.40	-25
3.5	.59	154	7.5	2.37	62	-20.4	.096	82	.41	-26
4.0	.60	149	6.3	2.06	57	-19.3	.108	83	.42	-28
4.5	.61	145	5.4	1.87	53	-18.1	.124	84	.42	- 33
5.0	.62	142	4.5	1.67	49	-17.3	.136	83	.43	-36
5.5	.64	137	3.8	1.54	44	-16.5	.150	85	.42	-4 0
6.0	.65	134	2.9	1.40	41	-15.7	.165	84	.44	-4 5

A model for this device is available in the DEVICE MODELS section.

AT-41400 Noise Parameters: $V_{CE} = 8 \text{ V}, I_{C} = 10 \text{ mA}$

Freq.	NFo	Γ	$R_N/50$		
GHz	dB	Mag	Ang	K _N /3U	
0.1	1.2	.12	3	0.17	
0.5	1.2	.10	15	0.17	
1.0	1.3	.06	27	0.16	
2.0	1.6	.24	163	0.16	
4.0	3.0	.52	-153	0.18	

AT-41400 Chip Dimensions



Note: Die thickness is 5 to 6 mil.